

## **Search Notes**



**Application/Control No.**

**Applicant(s)/Patent under  
Reexamination**

10/658.870

ONEDA ET AL.

**Examiner**

## Art Unit

Yon Couso

2624

**SEARCHED**

## INTERFERENCE SEARCHED

| Class | Subclass        | Date   | Examiner |
|-------|-----------------|--------|----------|
| PT    | Pat searched    |        |          |
|       | Intergene       |        |          |
|       | Search included | 1-6-08 | Gr       |

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

| DATE                       | EXMR      |
|----------------------------|-----------|
| East searched              |           |
| IEEE author<br>searched    | 1-6-08 un |
| PALM inventors<br>searched |           |
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